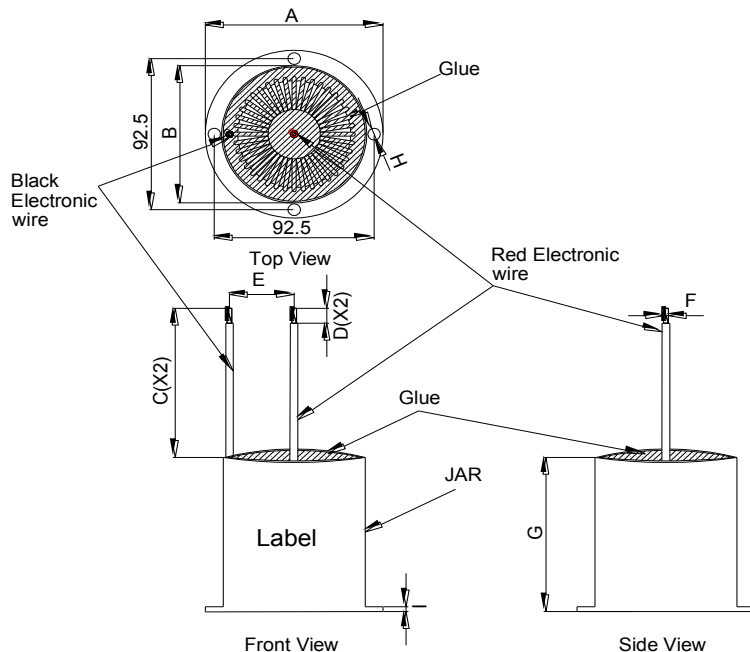


CUSTOMER	*	REV NO	1.1
DESCRIPTION	Inductor, 1.42mH, 35.0A, 42.0mΩDCR	PAGE NO	1 of 4
PART NO	L30864-1P	DATE	2015.03.27

1. CONFIGURATIONS & DIMENSIONS:



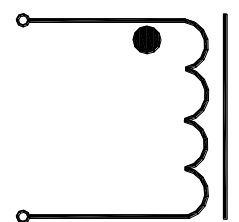
A	107.00	(Max.)	mm
B	83.00	(Max.)	mm
C	600.00	± 10.00	mm
D	12.00	± 3.00	mm
E	32.00	(Ref.)	mm
F	Φ7.0	(Max.)	mm
G	106.50	(Max.)	mm
H	Φ4.50	± 0.50	mm
I	2.80 Min. (3.20 typ.)		mm

Marking: L30864-1P
YYWW YY:Year, WW:Week.

2. ELECTRICAL CHARACTERISTICS:

TEST	CONDITION	Ta@25°C
1KHz 1.0V	L	1.42 mH ± 10%
Ta=25°C	DCR	42.00 mΩ (Max.)
1KHz 1.0V Isat1=22.0A	L@Isat1	1.05 mH (Typical)
1KHz 1.0V Isat2=32.0A	L@Isat2	0.81 mH (Typical)
1KHz 1.0V Irms=35.0A	L@Irms	0.74 mH (Typical)
Note	1.Isat1: DC current that will cause inductance to drop approx.30% (typ.) Isat2: DC current that will cause inductance to drop approx.40% (typ.) 2.Irms: DC current will caused an approx. temperature of 20°C rise (typ.)	

3. SCHEMATIC DIAGRAM



Wire : 200°C

Operating temperature range: -55°C ~ +130°C

4. TEST INSTRUMENTS

L:WK3260B.

DCR:Gain Kai Ta 502BCOIM.

L@Irms & L@Imax:WK3260B and WK3265B.

APPROVED BY	CHECKED BY	DRAWN BY
Royi Luo	Royi Luo	Anthony Yan



SPECIFICATION FOR APPROVAL



CUSTOMER	*	REV NO	1.1
DESCRIPTION	Inductor, 1.42mH, 35.0A, 42.0mΩDCR	PAGE NO	2 of 4
PART NO	L30864-1P	DATE	2015.03.27

5.TEST DATA FOR MECHANICAL

TEST ITEM	A mm	B mm	C mm	D mm	E mm	F mm	G mm	H mm	I mm	J mm
SPEC	107.00 (Max.)	83.00 (Max.)	600.00 ± 10.00	12.00 ± 3.00	32.00 (Ref.)	Φ7.0 (Max.)	106.50 (Max.)	Φ4.50 ± 0.50	2.80 Min. (3.20 typ.)	
1	105.66	81.38	600.25	11.89	32.26	6.05	105.88	4.53	3.22	
2	105.72	81.62	603.36	12.56	33.22	5.88	105.62	4.48	3.16	
3	105.62	81.58	602.50	12.70	32.54	6.11	105.66	4.64	2.95	
4	105.58	81.63	601.22	12.36	31.86	6.02	106.10	4.50	3.23	
5	105.36	81.54	605.32	12.08	32.23	5.78	105.40	4.38	3.12	
6										
7										
8										
9										
10										
AVERAGE	105.588	81.550	602.530	12.318	32.422	5.968	105.732	4.506	3.136	

REMARK:

APPROVED BY Roi Luo	CHECKED BY Roi Luo	DRAWN BY Anthony Yan
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SPECIFICATION FOR APPROVAL



CUSTOMER	*	REV NO	1.1
DESCRIPTION	Inductor, 1.42mH, 35.0A, 42.0mΩDCR	PAGE NO	3 of 4
PART NO	L30864-1P	DATE	2015.03.27

6. TEST DATA FOR ELECTRICAL

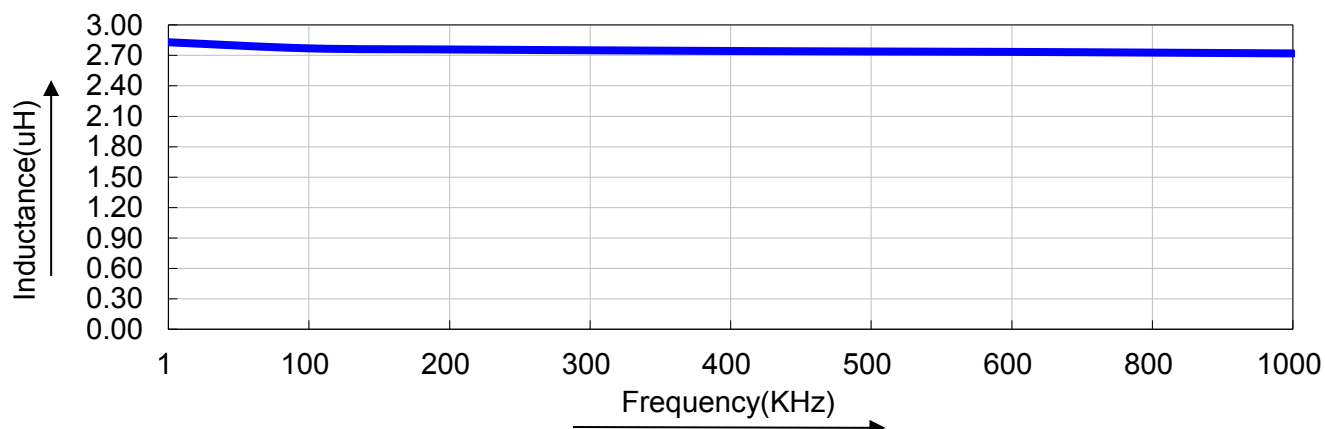
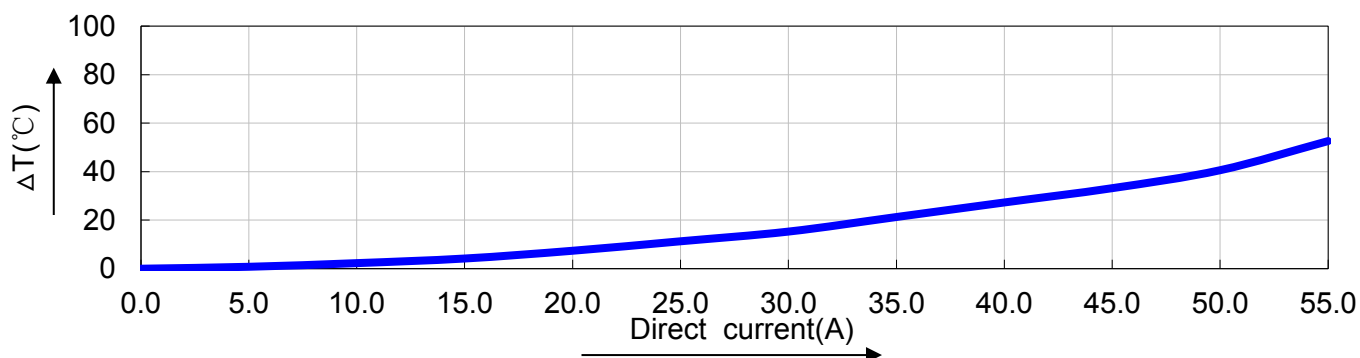
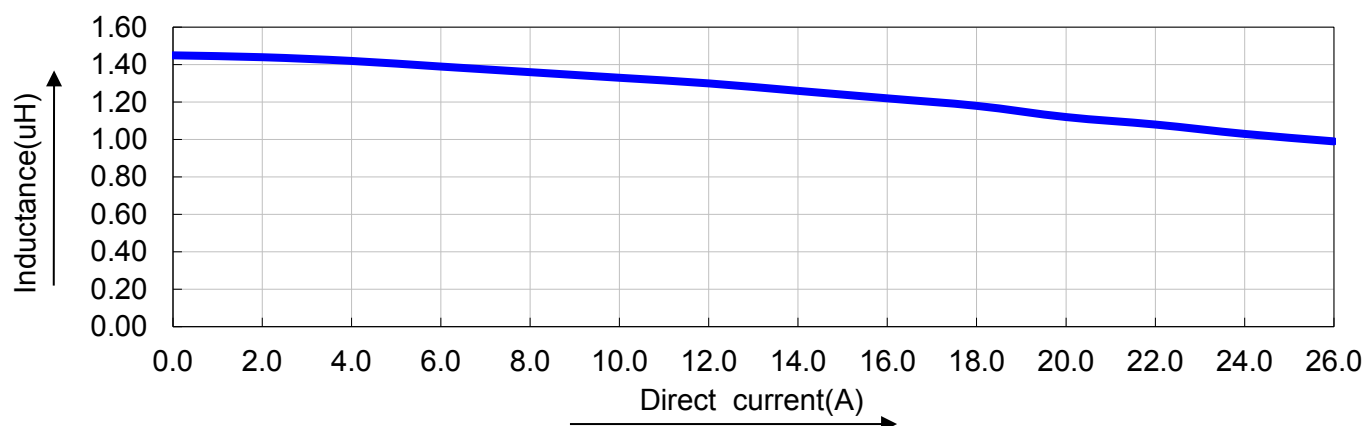
TEST ITEM	L mH	DCR mΩ	L@Isat1 mH	L@Isat2 mH	L@Irms mH	
CONDITION	1KHz 1.0V	at 25°C	1KHz 1.0V Isat1=22.0A	1KHz 1.0V Isat2=32.0A	1KHz 1.0V Irms=35.0A	
SPEC	1.42 ± 10%	42.00 (Max.)	1.05 (Typical)	0.81 (Typical)	0.74 (Typical)	
1	1.42	34.22	1.85	1.54	0.74	
2	1.46	34.52	1.85	1.57	0.76	
3	1.45	34.36	1.88	1.58	0.76	
4	1.45	34.55	1.83	1.52	0.76	
5	1.44	34.68	1.86	1.55	0.75	
6						
7						
8						
9						
10						
AVERAGE	1.4440	34.4660	1.8540	1.5520	0.7523	

REMARK:

APPROVED BY Richard Wen	CHECKED BY Royi Luo	DRAWN BY Anthony Yan
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CUSTOMER	*	REV NO	1.1
DESCRIPTION	Inductor, 1.42mH, 35.0A, 42.0mΩDCR	PAGE NO	4 of 4
PART NO	L30864-1P	DATE	2015.03.27

7.ELECTRICAL CHARACTERISTICS.



APPROVED BY

Royi Luo

CHECKED BY

Royi Luo

DRAWN BY

Anthony Yan

PACKAGING



CUSTOMER	*	VERSION	1.1
DESCRIPTION	Inductor,1.42mH, 35.0A, 42.0mΩDCR	PAGE NO	1 of 1
PART NO	L30864-1P	DATE	2015.03.27

8.PACKAGE SPECIFICATION.

8.1.Drawings (Unit:mm)

1PCS / Box.

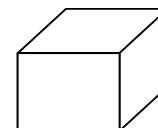
4Box / Inner Carton

Inner Carton=1PCS x 4Box=4PCS

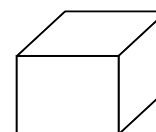
Inner Carton=Master Carton

Quantity:Total 4PCS

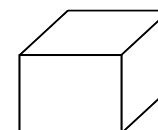
(1)Box



(2)Inner Carton



(3)Master Carton



NO	PACKAGING PART	REFERENCE DIMENSION	MATERIAL	QUANTITY
1	Box	140 x 140 x 170(mm)	K=K	1PCS / Box
2	Inner Carton	295 x 295 x 205(mm)	A=B	4 Box / Inner Carton
3	Master Carton	313 x 317 x 240 (mm)	A=A	Inner Carton / Master Carton

Note:WEIGHT: N.W:2.45Kg/PCS TOTAL9.80Kg(APPROX),G.W:TOTAL11.30Kg(APPROX);

Storage

- 1.To maintain the solderability of PIN and to keep the packing material in good condition, temperature and humidity in the storage area should be controlled.
- 2.Recommended conditions: -10℃~40℃, 70%RH (Max.)
- 3.Even under ideal storage conditions, solderability of products electrodes may decrease as time passes. For this reason, product should be used with one year from the time of delivery.
- 4.In case of storage over 6 months, solderability shall be checked before actual usage.

APPROVED BY	CHECKED BY	DRAWN BY
Royi Luo	Royi Luo	Anthony Yan

SPECIFICATION FOR APPROVAL



CUSTOMER	*	REV NO	1.1
DESCRIPTION	Inductor, 1.42mH, 35.0A, 42.0mΩDCR	PAGE NO	1 of 1
PART NO	L30864-1P	DATE	2015.03.27
1.RELIABILITY TEST.			
TEST ITEMS	SPECIFICATIONS	TEST METHOD AND REMARKS	
Solder ability	The electrodes shall be at least 90% covered with new solder coating	According to IEC68-2-20; 1. Soldering temperature: 245±5°C 2. Solder: 99.3Sn/0.7Cu 3. Flux: Rosin 4. Immersion time: 5±1Sec	
Soldering heat resistance	1. Appearance :no damage 2. Inductance change: within ±10% of initial value	1. Preheat temperature 150°C 2. Preheat time: 1min 3. Solder temperature 260±5°C 4. Dipping time: 10±1Sec 5. Measured at room temperature after placing for 24 hours	
Vibration(OUT LAB)	1. Appearance: no damage 2. All Electrical and mechanical parameters within tolerance	According to MIL-STD202 Method 204; 1. Frequency: 10 to 55Hz 2. Amplitude: 1.52mm 3. Direction and time X Y and Z Direction for 2 hours each	
Humidity resistance test	1. Appearance: no damage 2. All Electrical and mechanical parameters within tolerance	According to IEC68-2-1 Method Ca; 1. Temp: 40±2°C 2. Humidity: 90%-95%RH 3. Test time: 500±2H 4. The component should be stabilized at normal condition for 24 Hours before test	
High temperature resistance test	1. Appearance: no damage 2. All Electrical and mechanical parameters within tolerance	According to IEC68-2-2; 1. Temperature: 85±3°C 2. Test time: 500+24H 3. The component should be stabilized at normal condition for 24 hours before test	
Low Temperature resistance test	1. Appearance: no damage 2. All Electrical and mechanical parameters within tolerance	According to IEC68-2-1 Method A(Ad); 1. Temperature: -40±3°C 2. Test time: 500+24H 3. The component should be stabilized at normal condition for 24 hours before test	
Temperature cycles test	1. Appearance: no damage 2. All Electrical and mechanical parameters within tolerance	According to IEC68-2-14 Method N(Nb); 1. High-temp: 85±3 duration: 30min 2. room -temp: 25±2°C Duration 3H 3. Low-temp: -40±3 Duration 30min 4. room-temp: 25±2°C Duration 3H 5. Number of cycle: 10 cycles 6. The component should be stabilized at normal condition for 24 hours before test	
APPROVED BY David Wong		CHECKED BY Royi Luo	DRAWN BY Billy Tang